



IFW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Kaoru MATSUKI et al.

Group Art Unit: 2856

Application No.: 10/614,203

Examiner: D. LARKIN

Filed: July 8, 2003

Docket No.: 116454

For: SURFACE PROFILE MEASURING INSTRUMENT AND SURFACE PROFILE
MEASURING METHOD

AMENDMENT UNDER 37 C.F.R. §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In reply to the January 23, 2006, Office Action, please consider the following:

Amendments to the Specification;

Amendments to the Claims as reflected in the listing of claims;

Amendments to the Drawings include attached replacement sheets; and

Remarks.